

Annex B: Measurement Results
Tested Model :X6843
Report Number: WSCT-ANAB-R&E260700067A-SAR

Measurement Report for Device, CHEEK, GSM 850, Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, Head Simulating Liquid	CHEEK, 0.00	GSM 850		836.600, 190	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

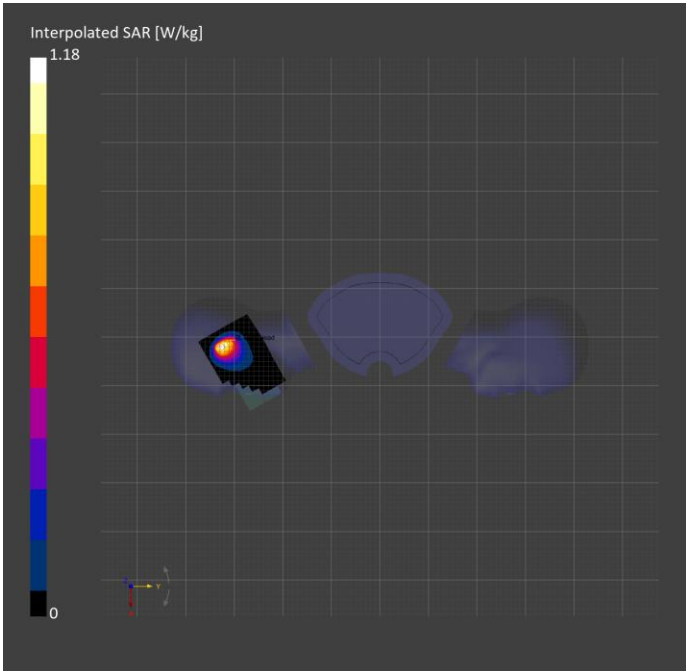
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.982	1.03
psSAR10g [W/kg]	0.615	0.558
Power Drift [dB]	0.00	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.9
Dist 3dB Peak [mm]		7.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, GSM 850, Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	GSM 850		836.600, 190	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

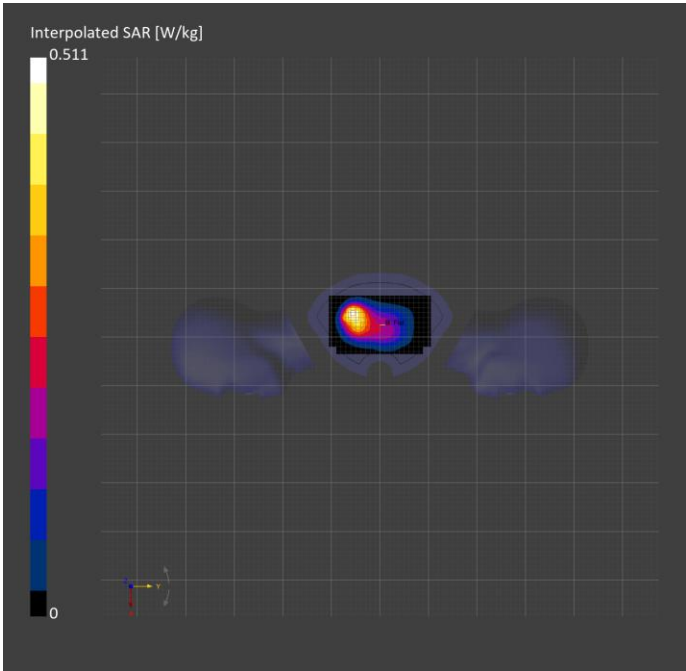
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.440	0.452
psSAR10g [W/kg]	0.294	0.277
Power Drift [dB]	0.04	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.2
Dist 3dB Peak [mm]		13.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	PCS 1900		1850.200, 512	7.69	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

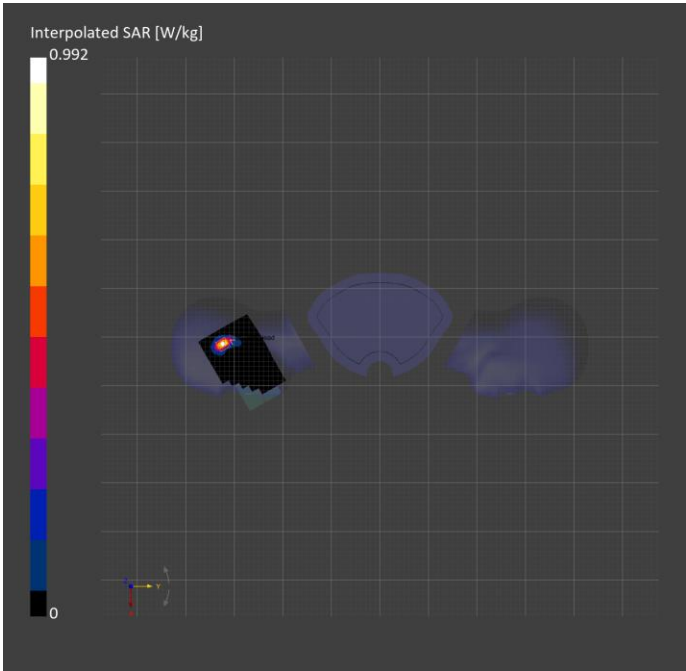
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.739	0.728
psSAR10g [W/kg]	0.332	0.318
Power Drift [dB]	-0.01	-0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.5
Dist 3dB Peak [mm]		6.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	PCS 1900		1850.200, 512	7.69	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

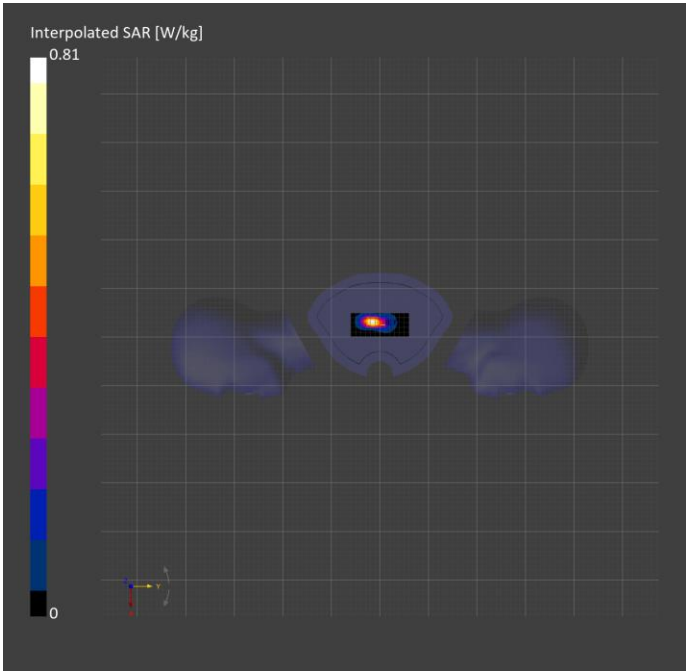
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.627	0.670
psSAR10g [W/kg]	0.306	0.324
Power Drift [dB]	-0.02	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.0
Dist 3dB Peak [mm]		7.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 2, Channel 9262 (1852.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 2		1852.400, 9262	7.69	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

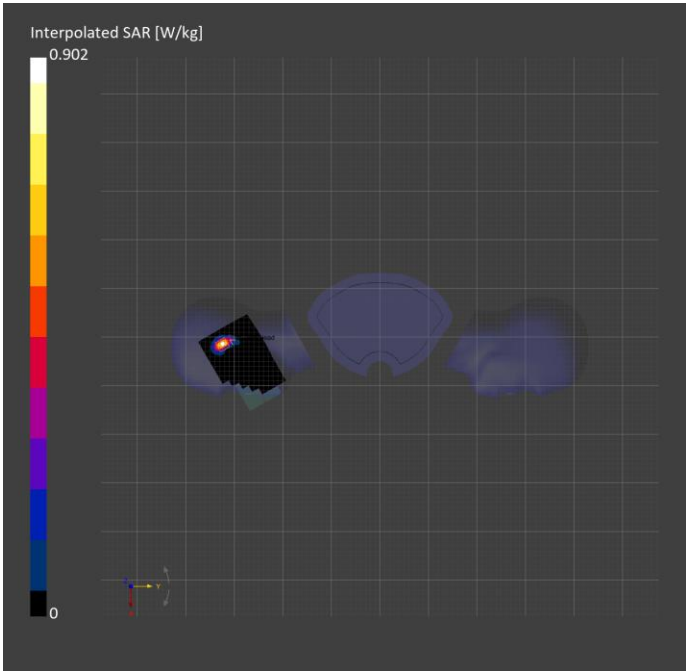
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.673	0.651
psSAR10g [W/kg]	0.303	0.280
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.5
Dist 3dB Peak [mm]		6.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, Band 2, Channel 9262 (1852.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	Band 2		1852.400, 9262	7.69	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

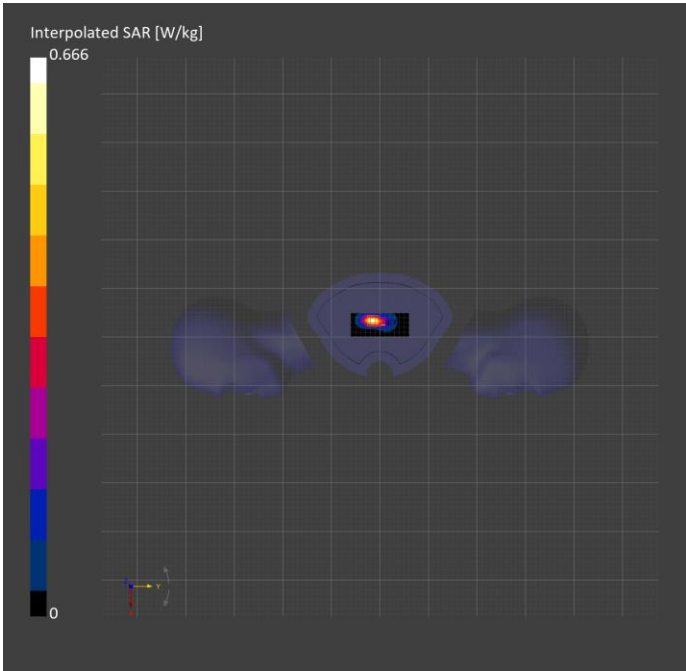
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.501	0.524
psSAR10g [W/kg]	0.243	0.255
Power Drift [dB]	-0.00	-0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.8
Dist 3dB Peak [mm]		8.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 4, Channel 1312 (1712.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 4		1712.400, 1312	7.84	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

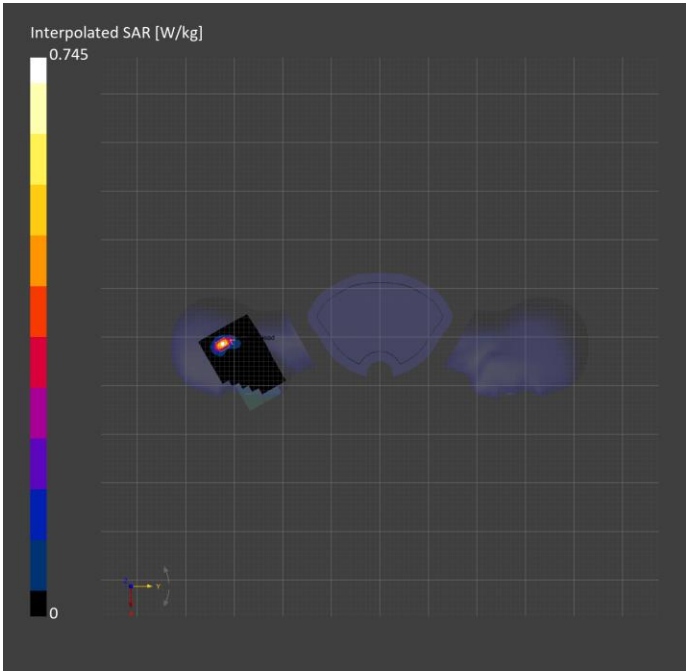
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-06	2026-08-06
psSAR1g [W/kg]	0.559	0.528
psSAR10g [W/kg]	0.256	0.232
Power Drift [dB]	-0.00	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.3
Dist 3dB Peak [mm]		6.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, Band 4, Channel 1312 (1712.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	Band 4		1712.400, 1312	7.84	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

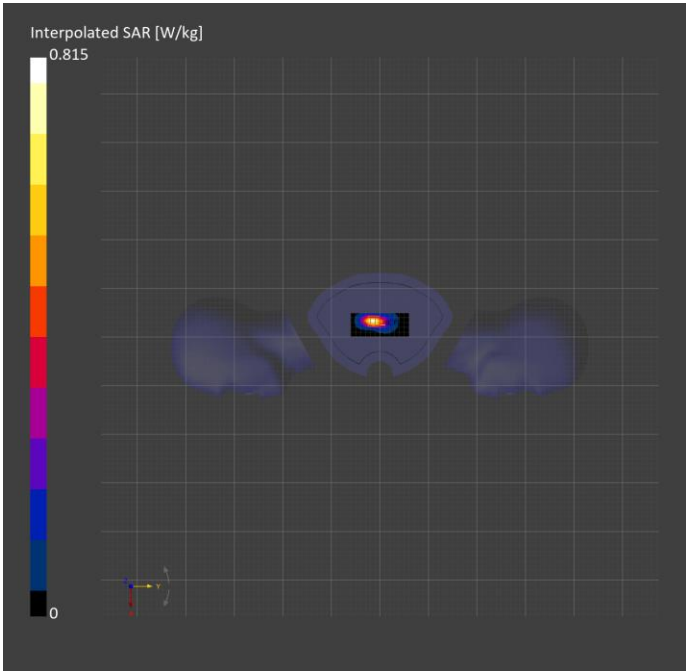
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-06	2026-08-06
psSAR1g [W/kg]	0.623	0.649
psSAR10g [W/kg]	0.311	0.327
Power Drift [dB]	-0.12	-0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.8
Dist 3dB Peak [mm]		8.4

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, Band 5, Channel 4132 (826.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, Head Simulating Liquid	TILT, 0.00	Band 5		826.400, 4132	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

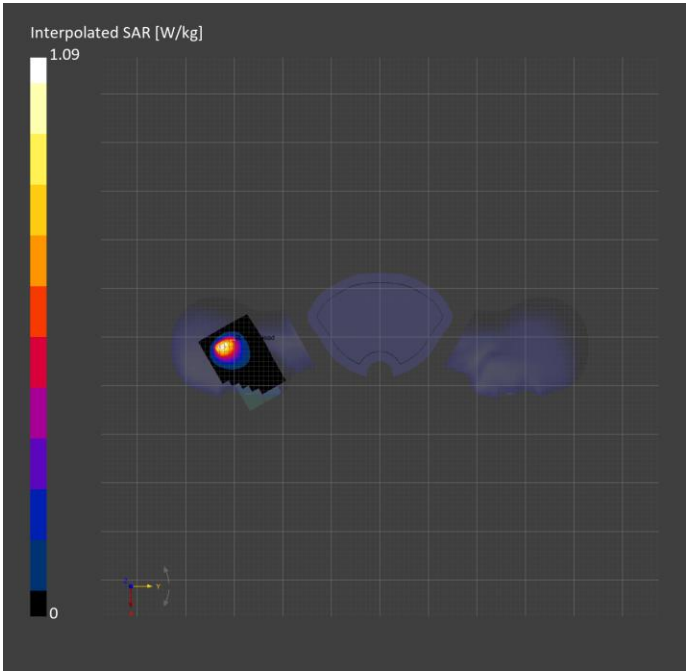
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.902	0.993
psSAR10g [W/kg]	0.567	0.525
Power Drift [dB]	-0.06	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.3
Dist 3dB Peak [mm]		7.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 5, Channel 4132 (826.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 5		826.400, 4132	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

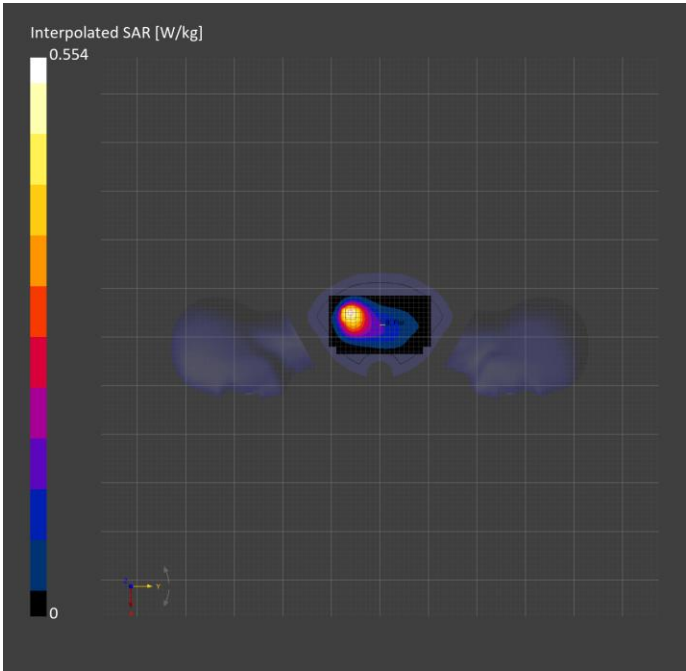
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.474	0.473
psSAR10g [W/kg]	0.315	0.295
Power Drift [dB]	-0.01	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.0
Dist 3dB Peak [mm]		13.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 2, Channel 18607 (1850.700MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 2		1850.700, 18607	7.69	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

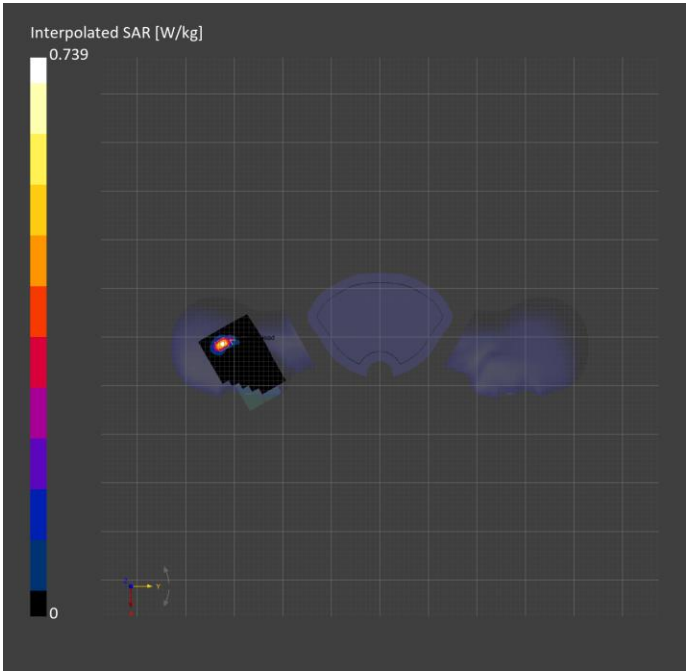
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.555	0.541
psSAR10g [W/kg]	0.251	0.231
Power Drift [dB]	-0.05	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.0
Dist 3dB Peak [mm]		5.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 2, Channel 18607 (1850.700MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 2		1850.700, 18607	7.69	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

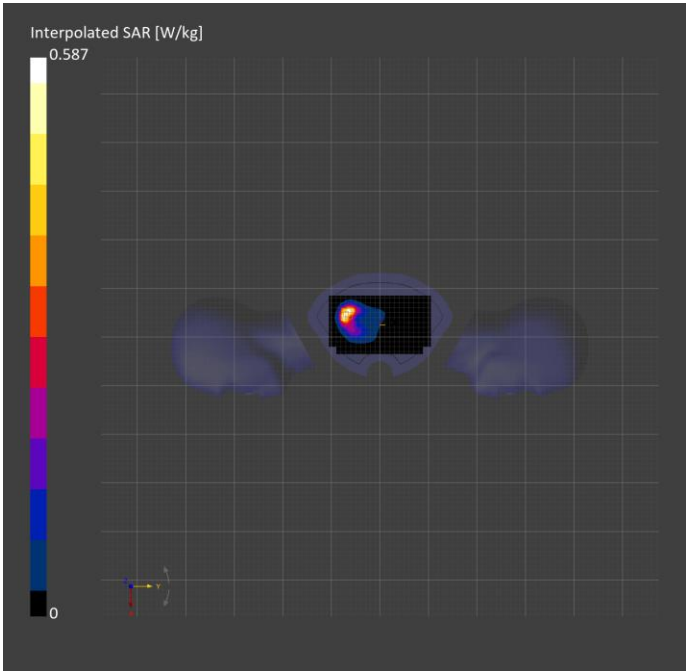
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.468	0.606
psSAR10g [W/kg]	0.262	0.296
Power Drift [dB]	-0.05	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.4
Dist 3dB Peak [mm]		8.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 4, Channel 20393 (1754.300MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 4		1754.300, 20393	7.84	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

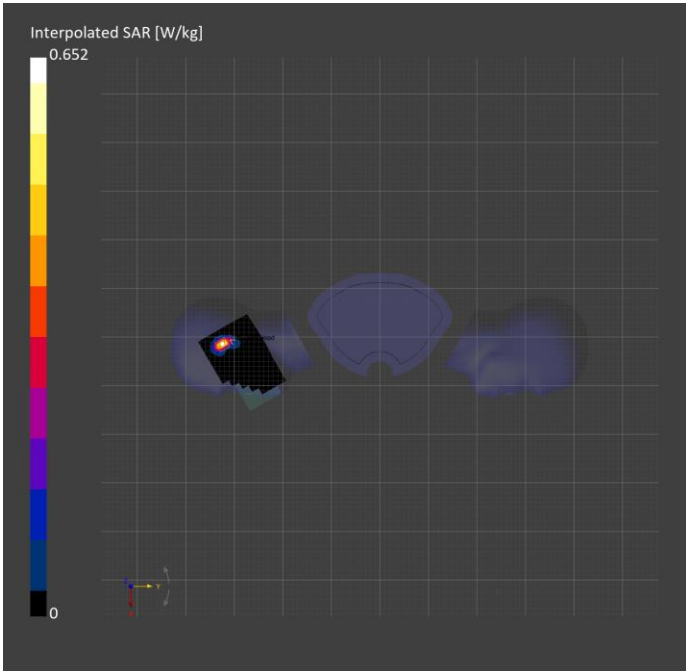
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-06	2026-08-06
psSAR1g [W/kg]	0.491	0.472
psSAR10g [W/kg]	0.227	0.205
Power Drift [dB]	0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.7
Dist 3dB Peak [mm]		5.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, Band 4, Channel 20393 (1754.300MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	Band 4		1754.300, 20393	7.84	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

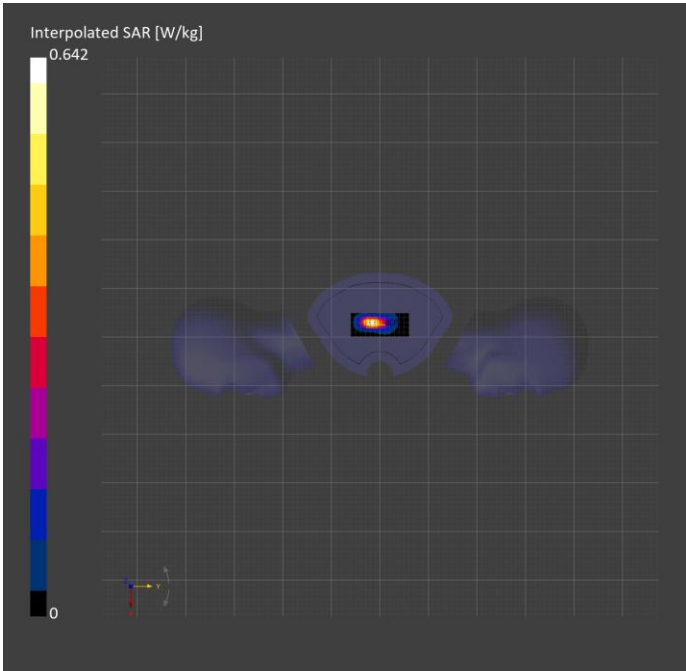
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-06	2026-08-06
psSAR1g [W/kg]	0.515	0.530
psSAR10g [W/kg]	0.261	0.268
Power Drift [dB]	-0.07	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.7
Dist 3dB Peak [mm]		8.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 5, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, Head Simulating Liquid	CHEEK, 0.00	Band 5		836.500, 20525	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

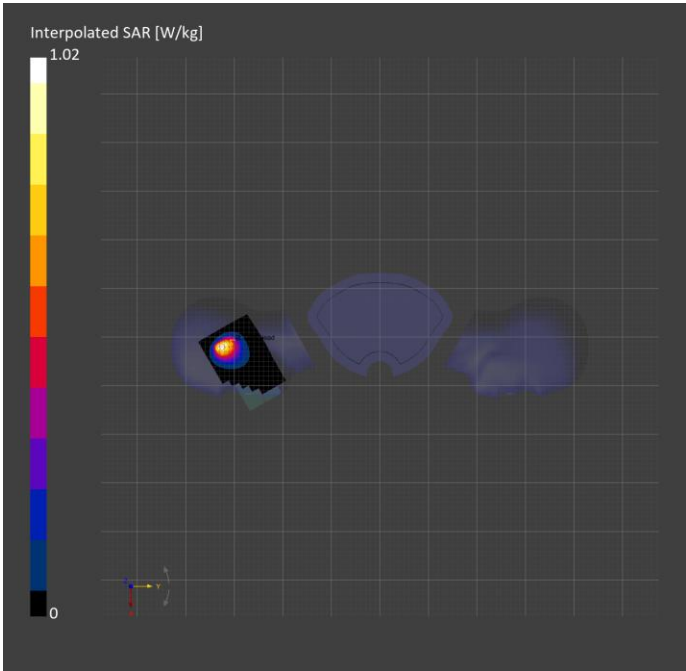
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-06	2026-08-06
psSAR1g [W/kg]	0.837	0.870
psSAR10g [W/kg]	0.523	0.465
Power Drift [dB]	-0.00	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		68.9
Dist 3dB Peak [mm]		6.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 5, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 5		836.500, 20525	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

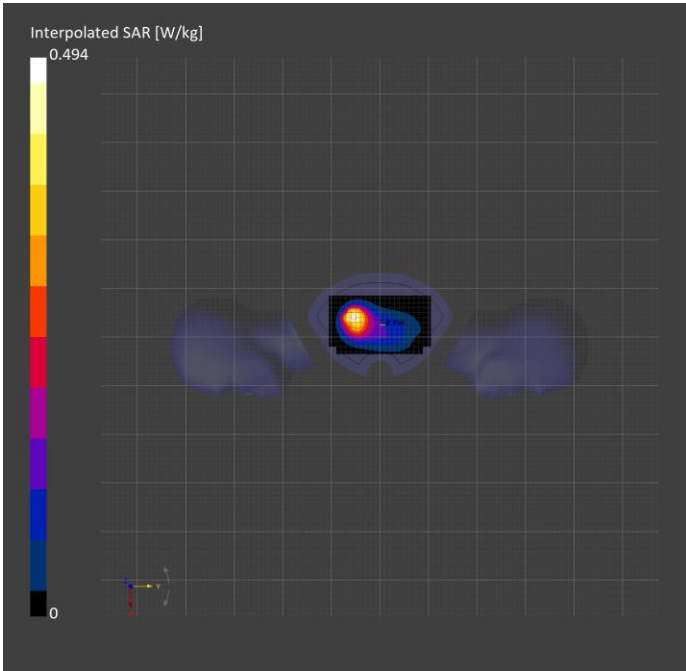
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.426	0.413
psSAR10g [W/kg]	0.281	0.254
Power Drift [dB]	-0.00	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		12.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 7, Channel 21350 (2560.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 7		2560.000, 21350	7.27	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

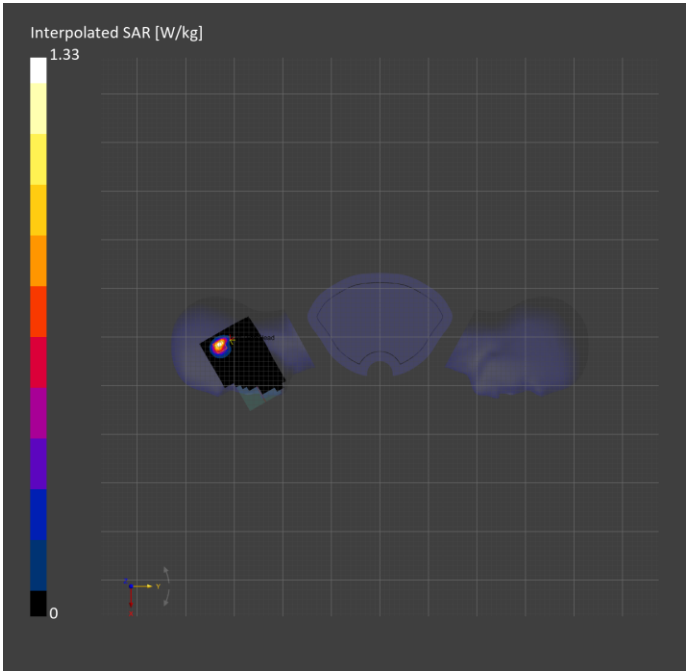
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.971	0.951
psSAR10g [W/kg]	0.433	0.405
Power Drift [dB]	-0.23	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.3
Dist 3dB Peak [mm]		7.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE TOP, Band 7,Channel 21350 (2560.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 10.00	Band 7		2560.000, 21350	7.27	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

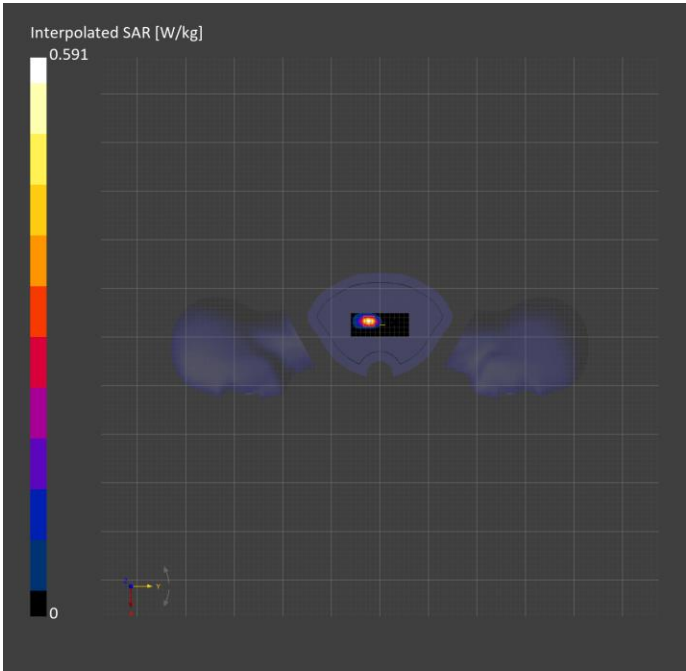
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.433	0.447
psSAR10g [W/kg]	0.187	0.192
Power Drift [dB]	-0.00	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		8.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 38, Channel 37800 (2575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 38		2575.000, 37800	7.27	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

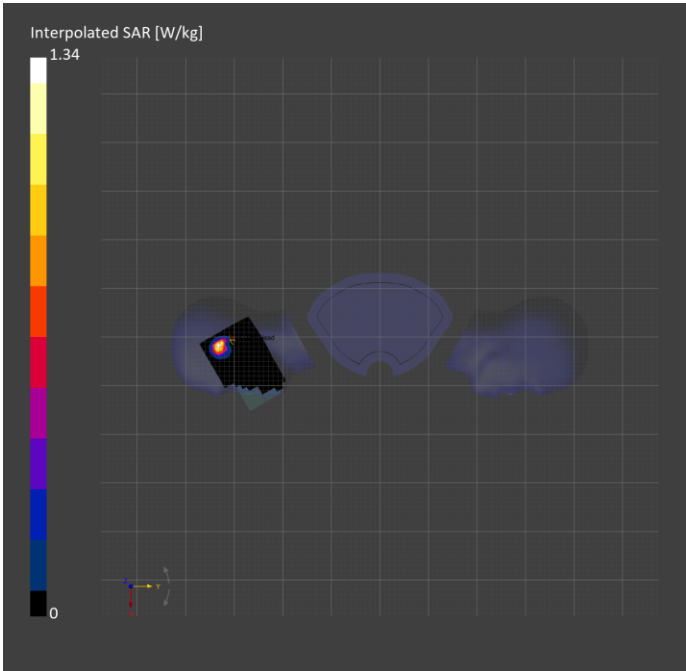
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.993	1.07
psSAR10g [W/kg]	0.466	0.468
Power Drift [dB]	0.13	0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.4
Dist 3dB Peak [mm]		7.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 38, Channel 37800 (2575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 38		2575.000, 37800	7.27	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

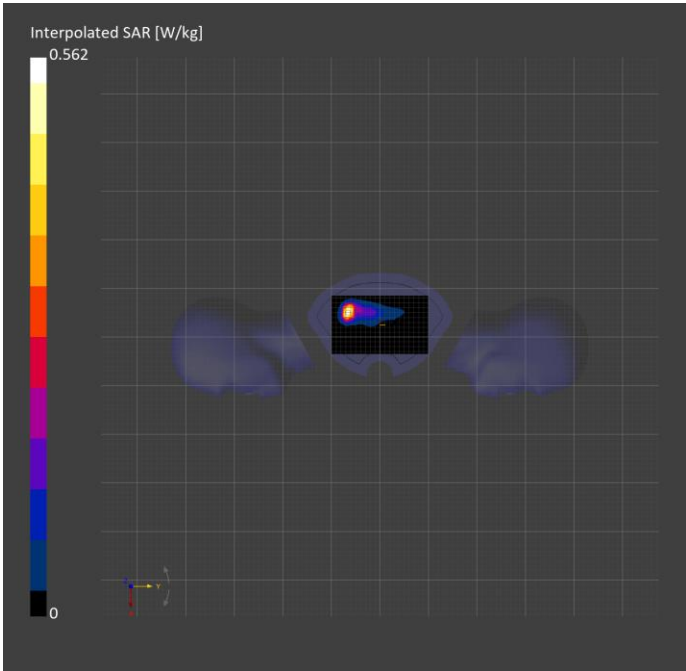
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.442	0.508
psSAR10g [W/kg]	0.215	0.222
Power Drift [dB]	-0.16	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.6
Dist 3dB Peak [mm]		8.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 41, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 41		2593.000, 40620	7.27	1.90	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

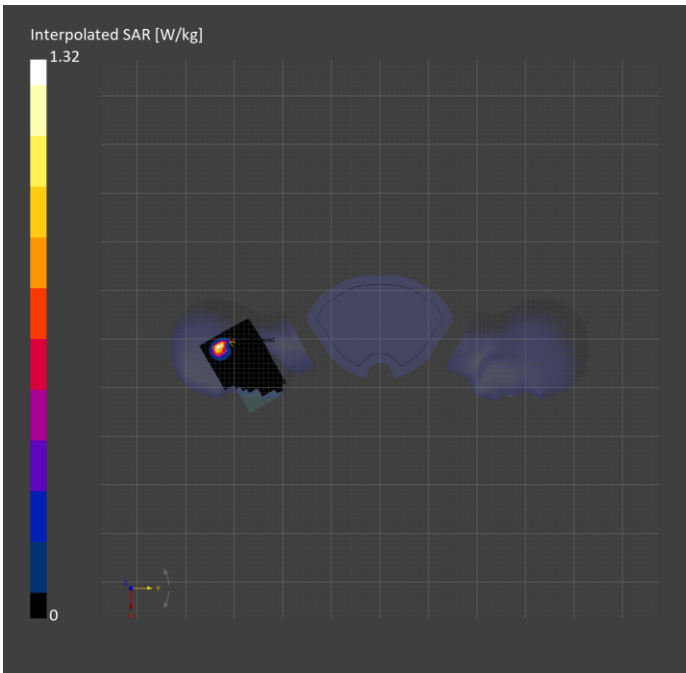
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-17	2026-08-17
psSAR1g [W/kg]	0.971	1.03
psSAR10g [W/kg]	0.443	0.438
Power Drift [dB]	0.02	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.8
Dist 3dB Peak [mm]		7.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 41, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 41		2593.000, 40620	7.27	1.90	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

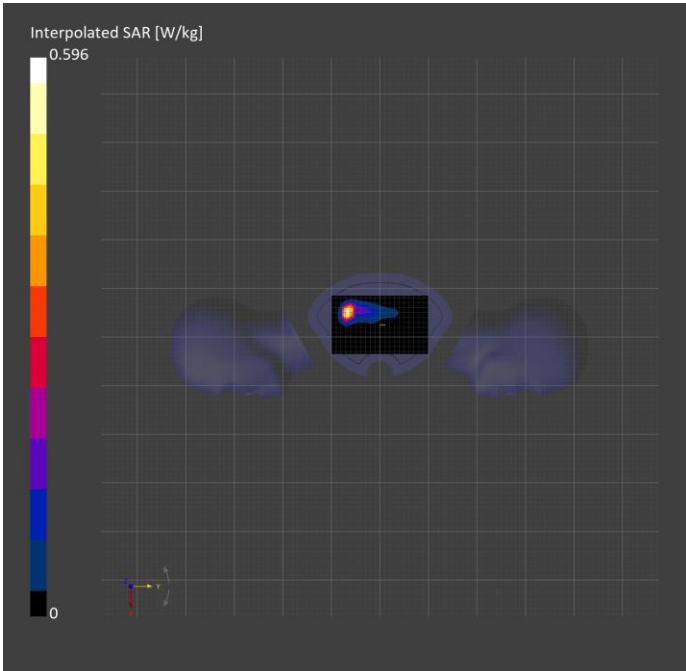
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-17	2026-08-17
psSAR1g [W/kg]	0.467	0.491
psSAR10g [W/kg]	0.219	0.214
Power Drift [dB]	0.04	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.4
Dist 3dB Peak [mm]		8.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, GSM 850, Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, Head Simulating Liquid	CHEEK, 0.00	GSM 850		836.600, 190	8.89	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

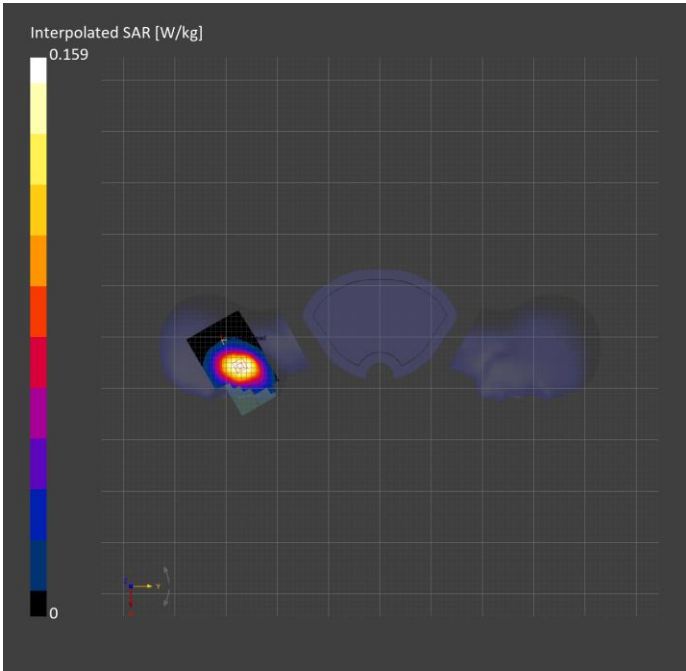
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.140	0.151
psSAR10g [W/kg]	0.097	0.121
Power Drift [dB]	-0.33	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.0
Dist 3dB Peak [mm]		> 15.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, GSM 850, Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	GSM 850		836.600, 190	8.89	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

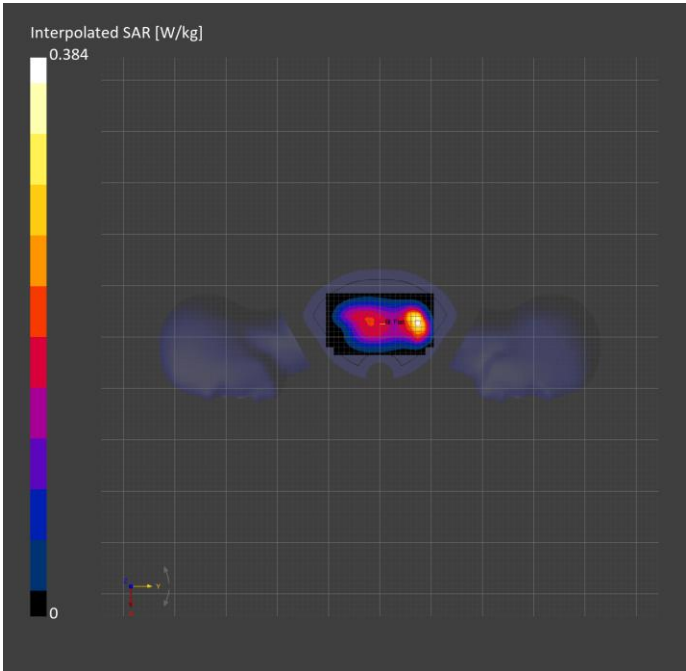
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.323	0.330
psSAR10g [W/kg]	0.207	0.201
Power Drift [dB]	-0.07	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.7
Dist 3dB Peak [mm]		12.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, TILT, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	TILT, 0.00	PCS 1900		1850.200, 512	7.33	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

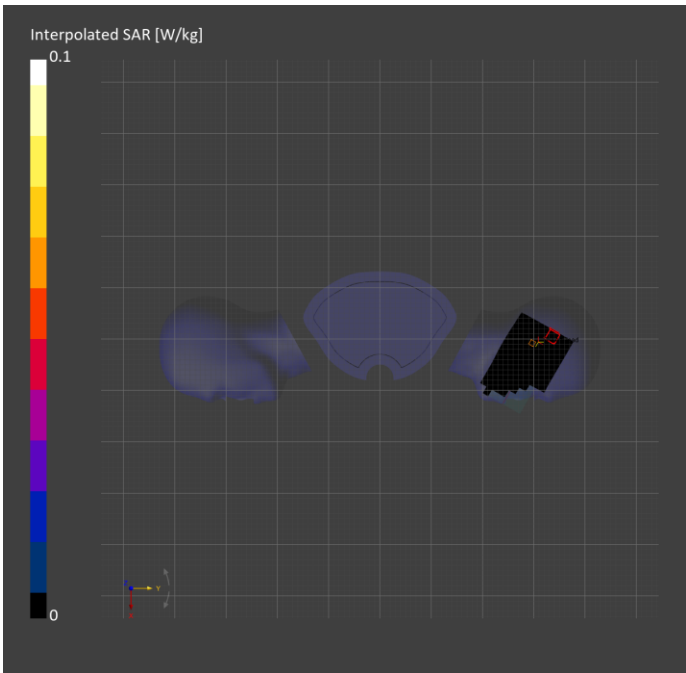
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.006	0.009
psSAR10g [W/kg]	0.003	0.005
Power Drift [dB]	-2.47	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.5
Dist 3dB Peak [mm]		8.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	PCS 1900		1850.200, 512	7.33	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

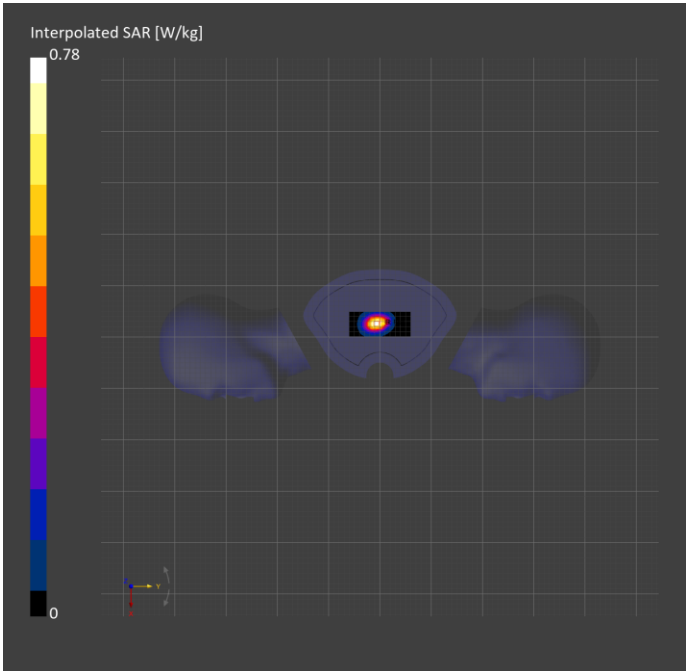
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.628	0.684
psSAR10g [W/kg]	0.343	0.394
Power Drift [dB]	-0.13	-0.18
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		12.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 2, Channel 18607 (1850.700MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 2		1850.700, 18607	7.33	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

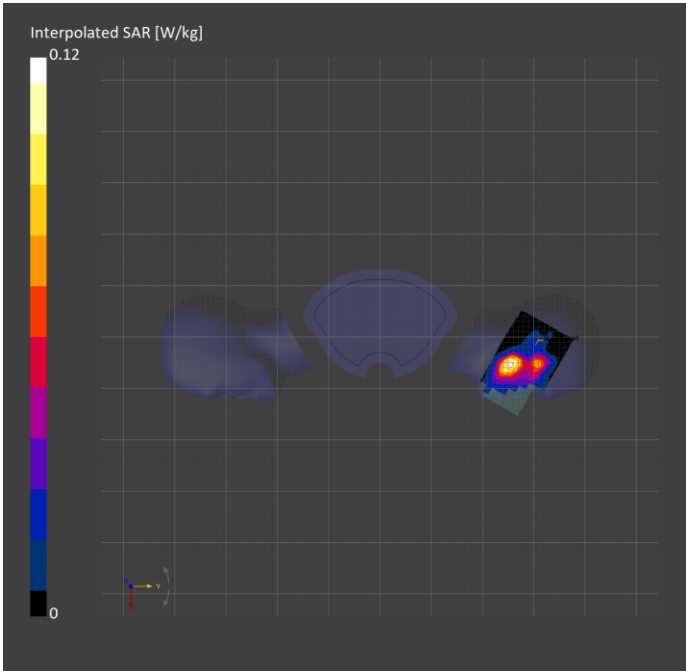
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.098	0.105
psSAR10g [W/kg]	0.058	0.070
Power Drift [dB]	-0.19	0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.4
Dist 3dB Peak [mm]		13.9

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 2, Channel 18607 (1850.700MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 2		1850.700, 18607	7.33	1.42	41.7

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

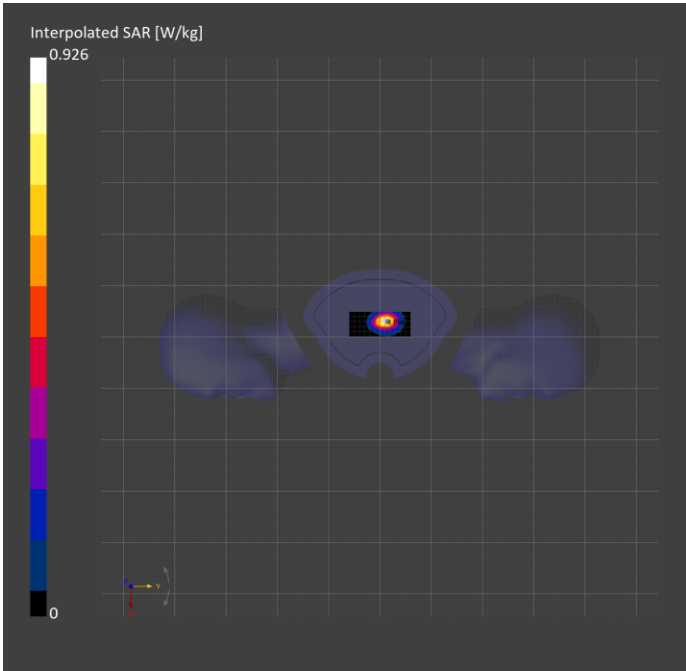
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-10	2026-08-10
psSAR1g [W/kg]	0.754	0.808
psSAR10g [W/kg]	0.413	0.474
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		12.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 4, Channel 20393 (1754.300MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 4		1754.300, 20393	7.6	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

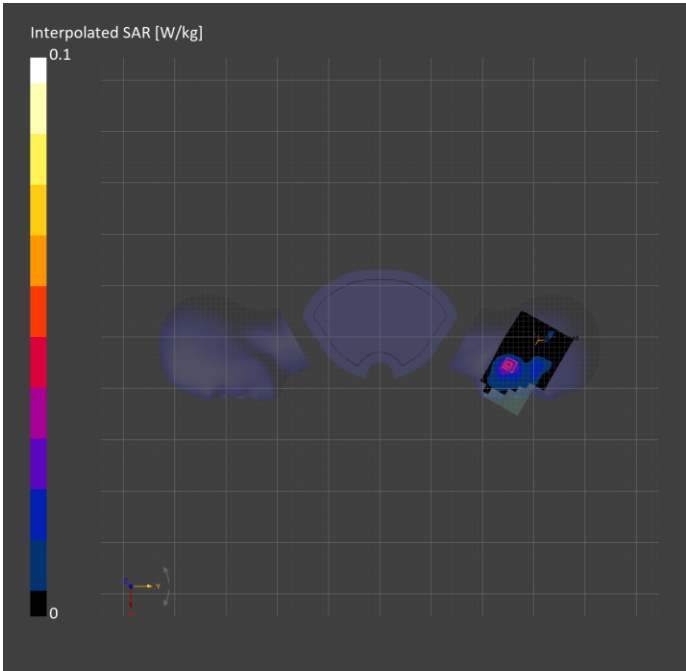
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-06	2026-08-06
psSAR1g [W/kg]	0.033	0.032
psSAR10g [W/kg]	0.020	0.023
Power Drift [dB]	-0.59	0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		94.5
Dist 3dB Peak [mm]		13.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 4, Channel 20393 (1754.300MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 4		1754.300, 20393	7.6	1.33	42.0

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

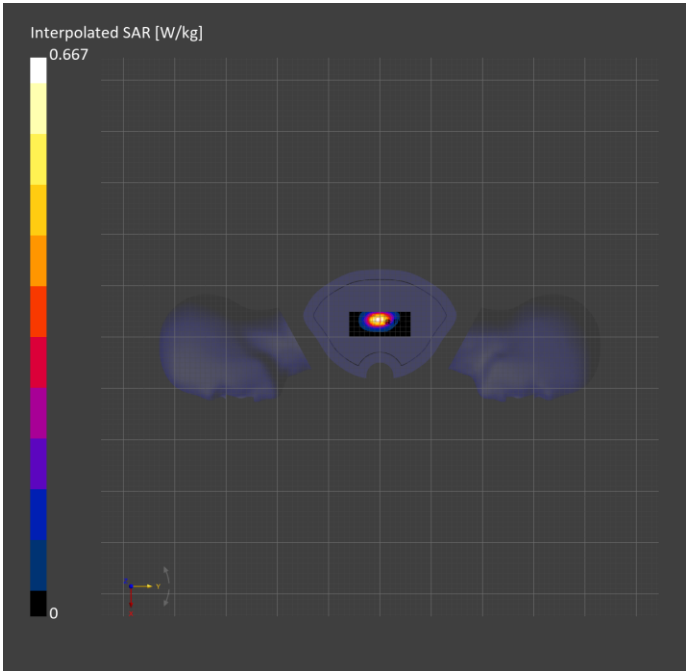
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-06	2026-08-06
psSAR1g [W/kg]	0.539	0.576
psSAR10g [W/kg]	0.293	0.335
Power Drift [dB]	-0.03	-0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.0
Dist 3dB Peak [mm]		10.3

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 5, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, Head Simulating Liquid	CHEEK, 0.00	Band 5		836.500, 20525	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

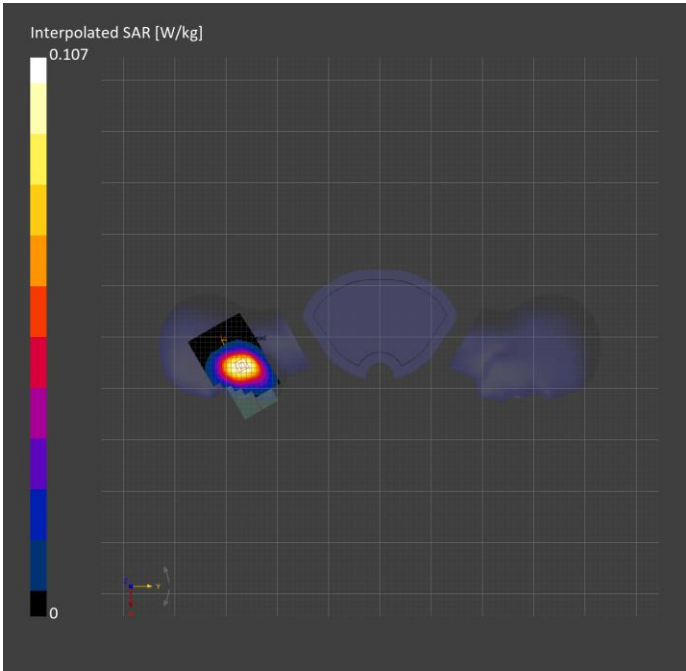
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.093	0.101
psSAR10g [W/kg]	0.064	0.079
Power Drift [dB]	0.05	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		96.9
Dist 3dB Peak [mm]		> 15.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, BACK, Band 5, Channel 20525 (836.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 10.00	Band 5		836.500, 20525	9.48	0.914	43.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

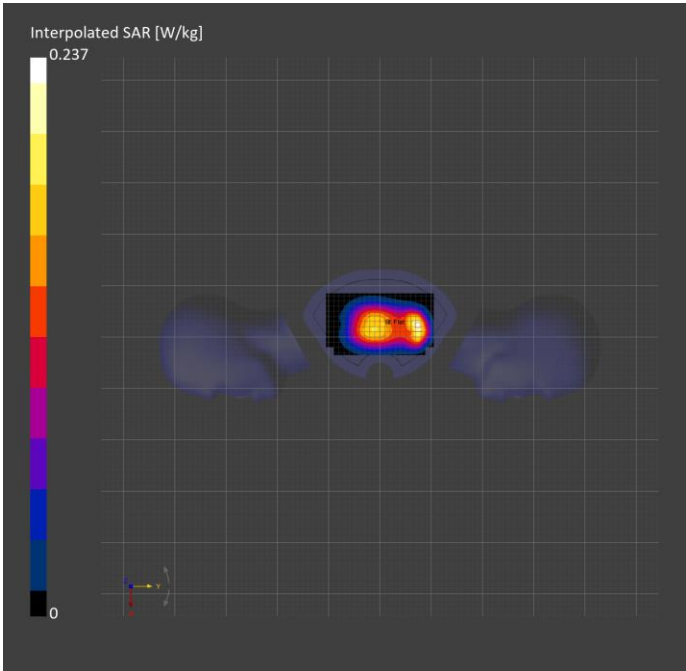
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-03	2026-08-03
psSAR1g [W/kg]	0.199	0.204
psSAR10g [W/kg]	0.128	0.122
Power Drift [dB]	0.10	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.7
Dist 3dB Peak [mm]		13.0

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 7, Channel 21350 (2560.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 7		2560.000, 21350	6.94	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

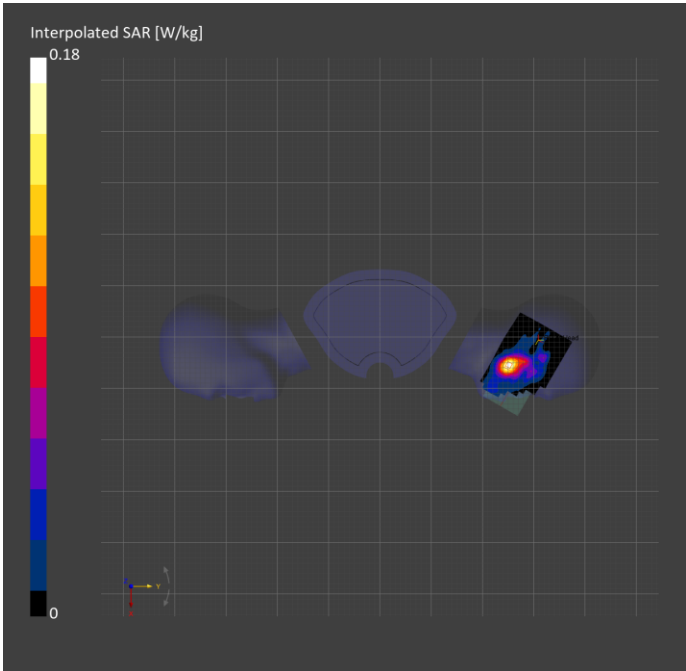
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.143	0.143
psSAR10g [W/kg]	0.075	0.082
Power Drift [dB]	-0.27	-0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.7
Dist 3dB Peak [mm]		12.1

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 7, Channel 21350 (2560.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 7		2535.000, 21100	6.94	1.89	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

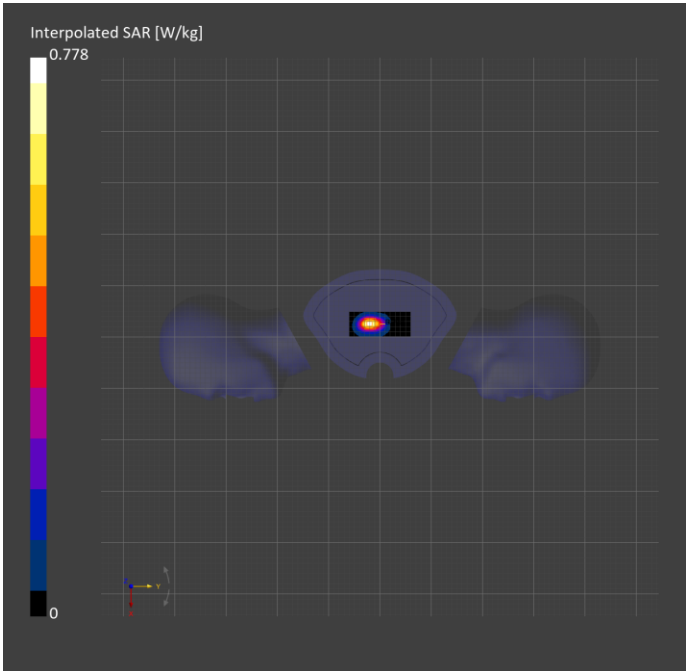
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.591	0.637
psSAR10g [W/kg]	0.286	0.332
Power Drift [dB]	-0.02	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.1
Dist 3dB Peak [mm]		10.8

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 38, Channel 37800 (2575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 38		2575.000, 37800	7.27	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

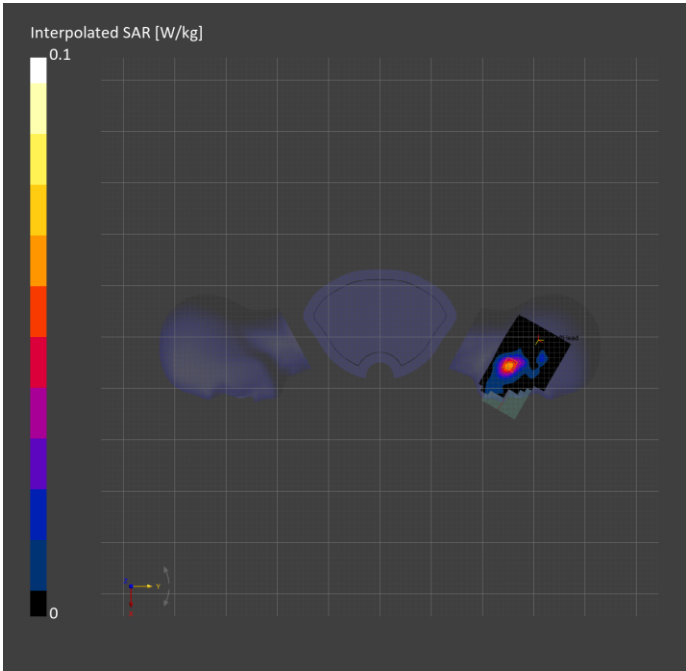
	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.053	0.054
psSAR10g [W/kg]	0.028	0.028
Power Drift [dB]	-0.06	-0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.1
Dist 3dB Peak [mm]		13.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, EDGE BOTTOM, Band 38, Channel 37800 (2575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE BOTTOM, 10.00	Band 38		2575.000, 37800	7.27	1.94	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

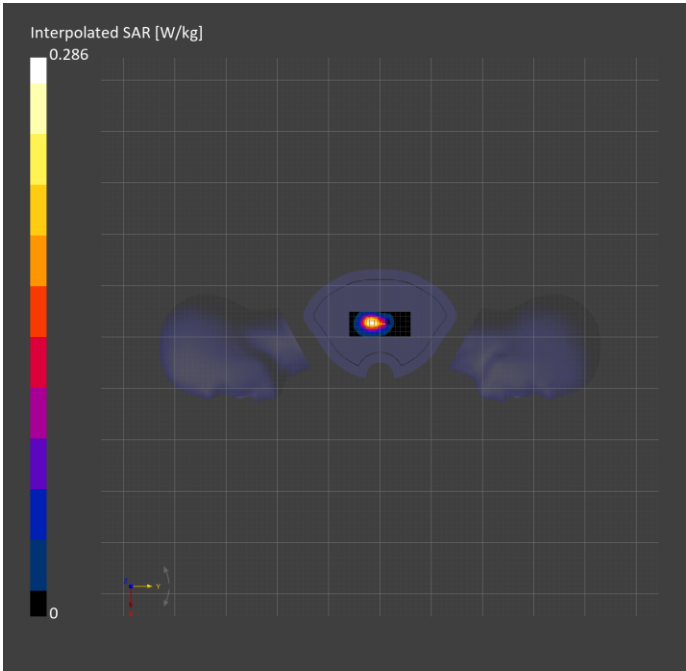
	Area Scan	Zoom Scan
Grid Extents [mm]	48.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	8.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-15	2026-08-15
psSAR1g [W/kg]	0.222	0.224
psSAR10g [W/kg]	0.108	0.110
Power Drift [dB]	-0.06	-0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.3
Dist 3dB Peak [mm]		10.5

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		



Measurement Report for Device, CHEEK, Band 41, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,			Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, Head Simulating Liquid	CHEEK, 0.00	Band 41		2593.000, 40620	7.27	1.90	40.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2219	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7956, 2025-09-30	DAE4ip Sn1925, 2025-10-15

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-08-17	2026-08-17
psSAR1g [W/kg]	0.071	0.076
psSAR10g [W/kg]	0.038	0.041
Power Drift [dB]	0.08	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.4
Dist 3dB Peak [mm]		13.2

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan
Warning(s)		
Error(s)		

